



FQP8N60C/FQPF8N60C

600V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

Features

- 7.5A, 600V, $R_{DS(on)}$ = 1.2 Ω @V_{GS} = 10 V Low gate charge (typical 28 nC)
- Low Crss (typical 12 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability



Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP8N60C	FQPF8N60C	Units
V_{DSS}	Drain-Source Voltage		600		V
I _D	Drain Current - Continuous (T _C = 25°C)		7.5	7.5 *	Α
	- Continuous (T _C = 100°C)		4.6	4.6 *	Α
I_{DM}	Drain Current - Pulsed	(Note 1)	30	30 *	Α
V _{GSS}	Gate-Source Voltage		± 30		V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	2	30	mJ
I _{AR}	Avalanche Current	(Note 1)	7	`.5	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	14	4.7	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5		V/ns
P_{D}	Power Dissipation (T _C = 25°C)		147	48	W
	- Derate above 25°C		1.18	0.38	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300		°C

^{*} Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FQP8N60C	FQPF8N60C	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.85	2.6	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink Typ.	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	to 25°C		0.7		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V				1	μΑ
		V _{DS} = 480 V, T _C = 125°C		-		10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3.75 A			1.0	1.2	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 3.75 A	(Note 4)		8.7		S
C _{iss}	Input Capacitance Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz			965 105	1255 135	pF pF
C _{rss}	Reverse Transfer Capacitance				12	16	pF
Switchi	ng Characteristics						
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_{D} = 7.5\text{A},$ $R_{G} = 25 \Omega$			16.5	45	ns
t _r	Turn-On Rise Time				60.5	130	ns
t _{d(off)}	Turn-Off Delay Time				81	170	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		64.5	140	ns
Qg	Total Gate Charge	$V_{DS} = 480 \text{ V}, I_D = 7.5\text{A},$ $V_{GS} = 10 \text{ V}$ (Note 4, 5)		-	28	36	nC
Q _{gs}	Gate-Source Charge			-	4.5		nC
Q _{gd}	Gate-Drain Charge				12		nC
Drain-S	ource Diode Characteristics ar	nd Maximum Ratings	5				
I _S	Maximum Continuous Drain-Source Diode Forward Current					7.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Forward Current				30	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 7.5 A				1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 7.5 \text{ A},$		-	365		ns
Q _{rr}	Reverse Recovery Charge	dl _F / dt = 100 A/μs	(Note 4)		3.4		μC

Notes:1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 7.3mH, I $_{AS}$ = 7.5 A, V $_{DD}$ = 50V, R $_{G}$ = 25.0, Starting T $_{J}$ = 25°C 3. I $_{SD}$ ≤ 7.5A, didt ≤ 200A/ $_{\mu S}$, V $_{DD}$ = 8 $_{DSS}$, Starting T $_{J}$ = 25°C 4. Pulse Test : Pulse width ≤ 300 $_{\mu S}$, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

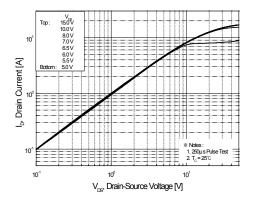


Figure 1. On-Region Characteristics

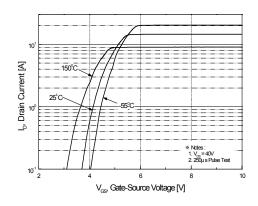


Figure 2. Transfer Characteristics

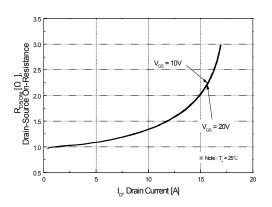


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

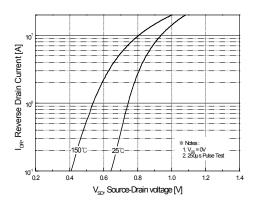


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

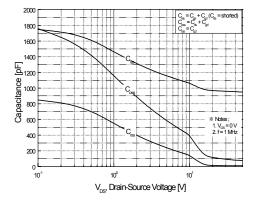


Figure 5. Capacitance Characteristics

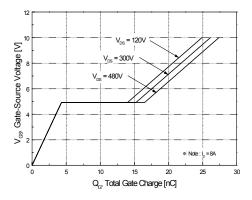


Figure 6. Gate Charge Characteristics

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200

150

Typical Characteristics (Continued)

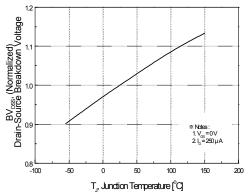


Figure 7. Breakdown Voltage Variation vs Temperature

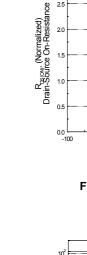


Figure 8. On-Resistance Variation vs Temperature

 $T_{_{J}}$, Junction Temperature [°C]

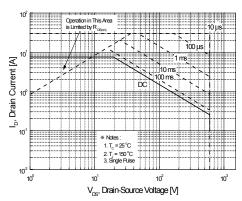


Figure 9-1. Maximum Safe Operating Area for FQP8N60C

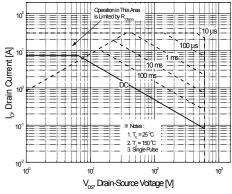


Figure 9-2. Maximum Safe Operating Area for FQPF8N60C

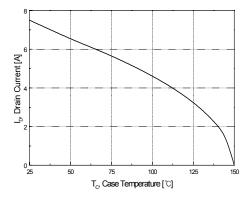


Figure 10. Maximum Drain Current vs Case Temperature

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Typical Characteristics (Continued)

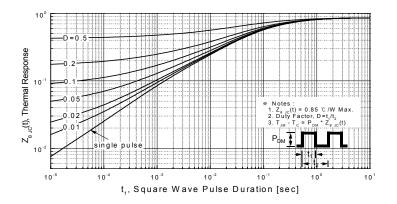


Figure 11-1. Transient Thermal Response Curve for FQP8N60C

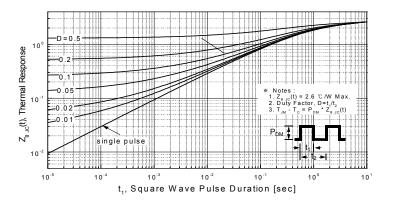
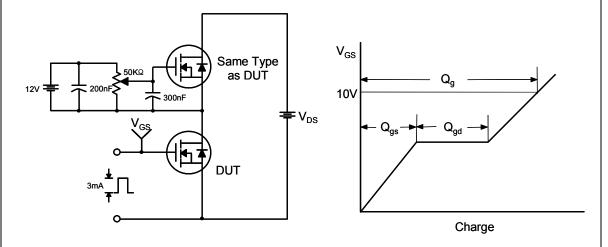


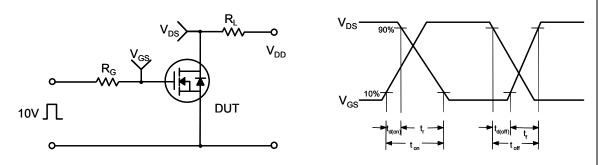
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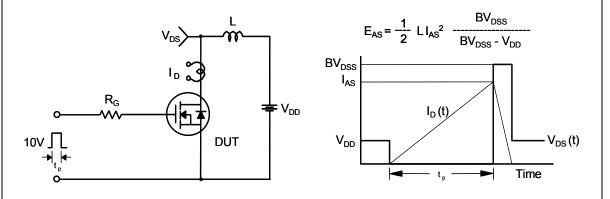
Gate Charge Test Circuit & Waveform



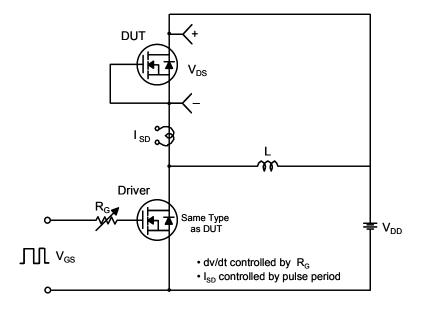
Resistive Switching Test Circuit & Waveforms

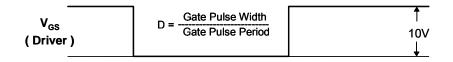


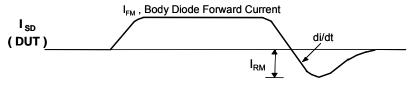
Unclamped Inductive Switching Test Circuit & Waveforms



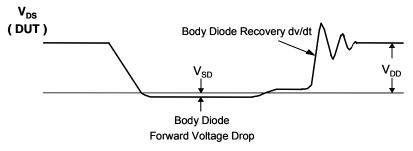
Peak Diode Recovery dv/dt Test Circuit & Waveforms

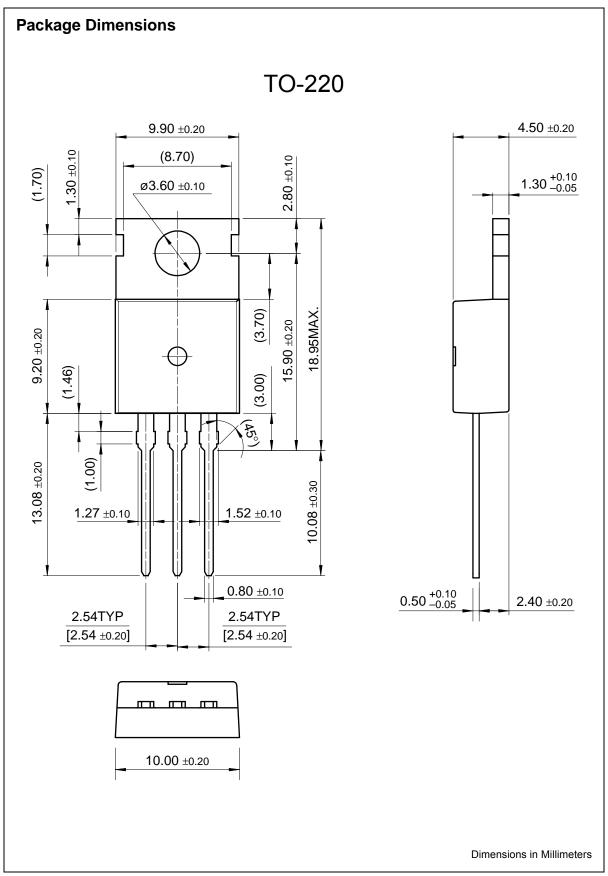


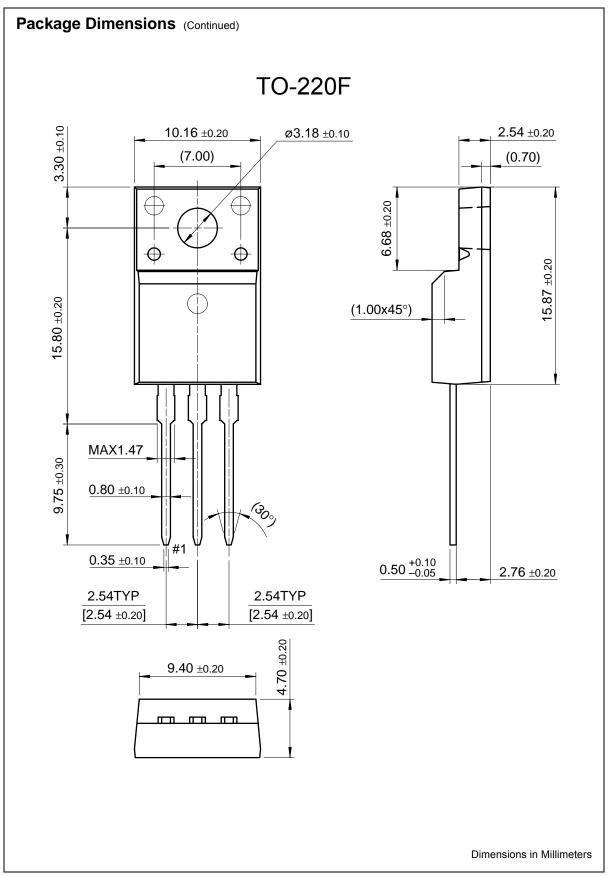




Body Diode Reverse Current







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